


<b>Search Notes</b>  	<b>Application/Control No.</b>  10047629	<b>Applicant(s)/Patent Under Reexamination</b>  MEYER, CONRAD K.
	<b>Examiner</b>  Wen-Tai Lin	<b>Art Unit</b>  2454

SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES		
Search Notes	Date	Examiner
Updated search on EAST (see printout)	12/11/09	wtl

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
709	203	12/11/09	wtl
707	10	12/11/09	wtl

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